

(4) 2/8/2004

PTO/SB/08A (02-03)

Approved for use through 04/30/2003. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Complete if Known	
		Application Number	10/771,590
		Filing Date	
		First Named Inventor	Chen et al.
		Art Unit	2155 ENG
		Examiner Name	
Sheet 1 of 1	Attorney Docket Number	H11231	

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
✓		US- 5,513,320	04/30/1996	Young et al.	Entire Document
		US- 5,812,774	09/22/1998	Kempf et al.	Entire Document
		US- 5,852,719	12/22/1998	Fisher et al.	Entire Document
		US- 5,870,627	02/09/1999	O'Toole et al.	Entire Document
		US- 6,049,842	04/11/2000	Garrett et al.	Entire Document
		US- 6,145,016	11/07/2000	Lai et al.	Entire Document
		US- 6,182,164 B1	01/30/2001	Williams	Entire Document
		US- 6,182,165 B1	01/30/2001	Spilo	Entire Document
		US- 6,199,124 B1	03/06/2001	Ramakrishnan et al.	Entire Document
		US- 6,212,593 B1	04/03/2001	Pham et al.	Entire Document
		US- 6,304,911 B1	10/16/2001	Breich et al.	Entire Document
		US- 6,324,595 B1	11/27/2001	Tsai et al.	Entire Document
		US- 6,327,615 B1	12/04/2001	Kasper	Entire Document
		US- 6,334,162 B1	12/25/2001	Garrett et al.	Entire Document
		US- 2002/0009075 A1	01/24/2002	Fesas, Jr.	Entire Document
		US- 2002/0013821 A1	01/31/2002	Kasper	Entire Document
		US- 6,401,145	B1	Baskey et al.	Entire Document
		US- 2002/0188742 A1	12/12/2002	Nie	Entire Document
		US- 6,515,993	B1	Williams et al.	Entire Document

2002.06

2003.02

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)			

m
2-12-09

Examiner Signature	PRIMARY EXAMINER <i>LS</i>	Date Considered	7/24/07
--------------------	----------------------------	-----------------	---------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.